

Search Notes

Application/Control No.

10/564,086

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

BIAIS, FRANCOIS

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	214	2/15/2006	HN
310	215	2/15/2006	HN
310	216	2/15/2006	HN
310	52	2/15/2006	HN
310	54	2/15/2006	HN
310	58	2/15/2006	HN
310	64	2/15/2006	HN
update search	All	6/22/07	HN
update search	All	12/7/07	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR